

Notice of References Cited

Application/Control No.

10/530,839

Applicant(s)/Patent Under
Reexamination
TERASHIMA ET AL.

Examiner

John P. Sheehan

Art Unit

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0116236 A1	06-2003	Hayakawa et al.	148/516
*	B	US-2001/0030001	10-2001	Hayakawa et al.	148/111
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
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	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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